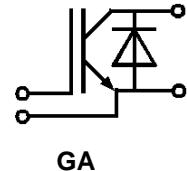


Absolute Maximum Ratings		Values	Units
Symbol	Conditions¹⁾		
V _{CES}		1200	V
V _{CGR}	R _{GE} = 20 kΩ	1200	V
I _c	T _{case} = 25/80 °C	400 / 360	A
I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	800 / 720	A
V _{GES}		± 20	V
P _{tot}	per IGBT, T _{case} = 25 °C	2750	W
T _j , (T _{stg})		- 40 . . . +150 (125)	°C
V _{isol}	AC, 1 min.	2 500 ⁷⁾	V
humidity climate	DIN 40 040	Class F	
	DIN IEC 68 T.1	40/125/56	
Inverse Diode			
I _F = - I _c	T _{case} = 25/80 °C	390 / 260	A
I _{FM} = - I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	800 / 720	A
I _{FSM}	t _p = 10 ms; sin.; T _j = 150 °C	2900	A
I _t ²	t _p = 10 ms; T _j = 150 °C	42000	A ² s

**SEMITRANS® M
IGBT Modules****SKM 400 GA 123 D****SEMITRANS 4****Features**

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 * I_{cnom}
- Latch-up free
- Fast & soft inverse CAL diodes⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (12 mm) and creepage distances (20 mm).

Characteristics	Conditions¹⁾	min.	typ.	max.	Units
V _{(BR)CES}	V _{GE} = 0, I _c = 4 mA	≥ V _{CES}	-	-	V
V _{GE(th)}	V _{GE} = V _{CE} , I _c = 12 mA	4,5	5,5	6,5	V
I _{CES}	V _{GE} = 0 { T _j = 25 °C	-	0,4	6	mA
	V _{CE} = V _{CES} } T _j = 125 °C	-	24	-	mA
I _{GES}	V _{GE} = 20 V, V _{CE} = 0	-	-	1	μA
V _{CEsat}	I _c = 300 A } V _{GE} = 15 V;	-	2,5(3,1)	3(3,7)	V
V _{CEsat}	I _c = 400 A } T _j = 25 (125) °C	-	2,8(3,6)	-	V
g _{fs}	V _{CE} = 20 V, I _c = 300 A	124	-	-	S
C _{CHC}		-	1300	1500	pF
C _{ies}	{ V _{GE} = 0	-	22	30	nF
C _{oes}	V _{CE} = 25 V	-	3,3	4	nF
C _{res}	f = 1 MHz	-	1,2	1,6	nF
L _{CE}		-	-	20	nH
t _{d(on)}	{ V _{CC} = 600 V	-	200	400	ns
t _r	V _{GE} = +15 V/-15V ³⁾	-	115	220	ns
t _{d(off)}	I _c = 300 A, ind. load	-	720	900	ns
t _f	R _{Gon} = R _{Goff} = 3,3 Ω	-	80	100	ns
E _{on} ⁵⁾	T _j = 125 °C	-	38	-	mWs
E _{off} ⁵⁾		-	40	-	mWs
Inverse Diode ⁸⁾					
V _F = V _{EC}	I _F = 300 A { V _{GE} = 0 V;	-	2,0(1,8)	2,5	V
V _F = V _{EC}	I _F = 400 A } T _j = 25 (125) °C	-	2,25(2,05)	-	V
V _{TO}	T _j = 125 °C ²⁾	-	-	1,2	V
r _T	T _j = 125 °C ²⁾	-	2,5	3,5	mΩ
I _{IRRM}	I _F = 300 A; T _j = 25 (125) °C ²⁾	-	85(140)	-	A
Q _{rr}	I _F = 300 A; T _j = 25 (125) °C ²⁾	-	13(40)	-	μC
Thermal Characteristics					
R _{thjc}	per IGBT	-	-	0,045	°C/W
R _{thjc}	per diode D	-	-	0,125	°C/W
R _{thch}	per module	-	-	0,038	°C/W

Typical Applications: → B6-187

- Switching (not for linear use)

¹⁾ T_{case} = 25 °C, unless otherwise specified

²⁾ I_F = - I_c, V_R = 600 V,
- dI_F/dt = 2000 A/μs, V_{GE} = 0 V

³⁾ Use V_{GEoff} = -5 ... -15 V

⁵⁾ See fig. 2 + 3; R_{Goff} = 3,3 Ω

⁷⁾ V_{isol} = 4000 V_{rms} on request

⁸⁾ CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B6-188
SEMITRANS 4

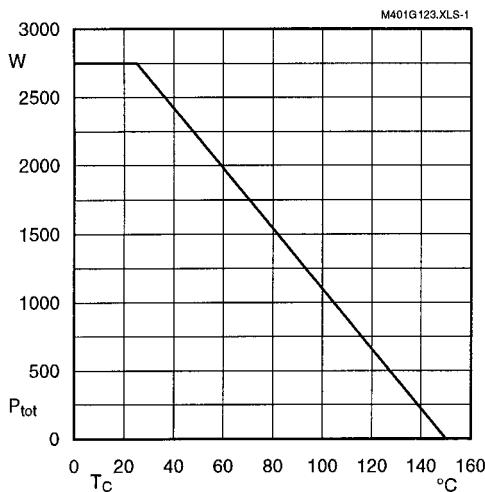


Fig. 1 Rated power dissipation $P_{tot} = f (T_C)$

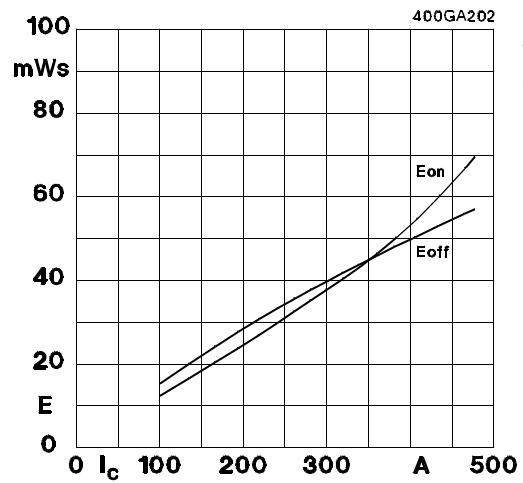


Fig. 2 Turn-on /-off energy = f (I_C)

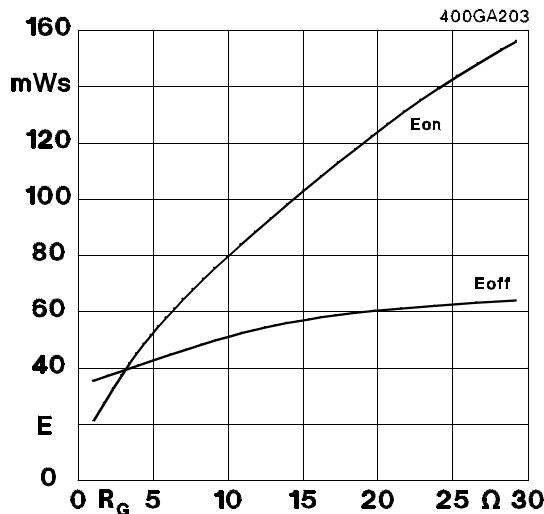


Fig. 3 Turn-on /-off energy = f (R_G)

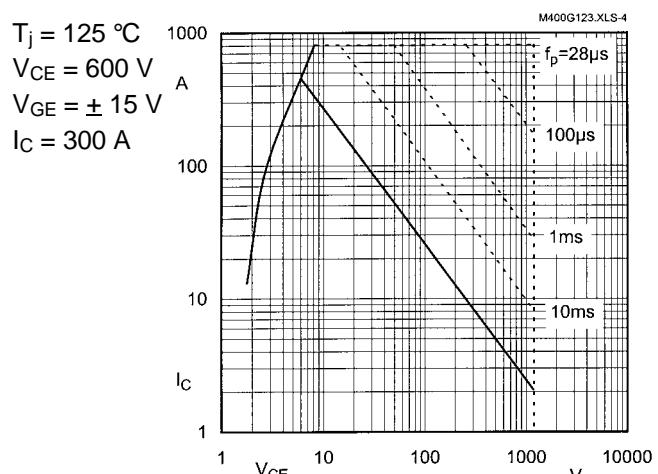


Fig. 4 Maximum safe operating area (SOA) $I_C = f (V_{CE})$

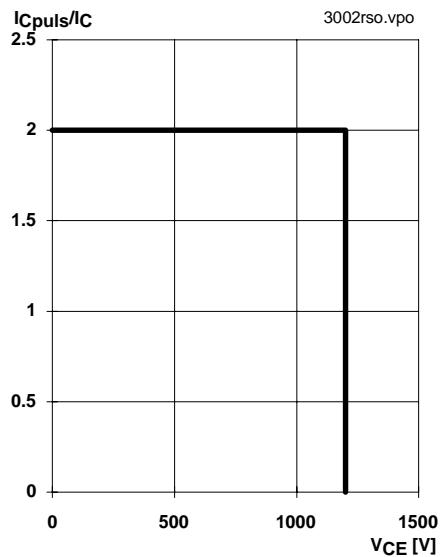


Fig. 5 Turn-off safe operating area (RBSOA)

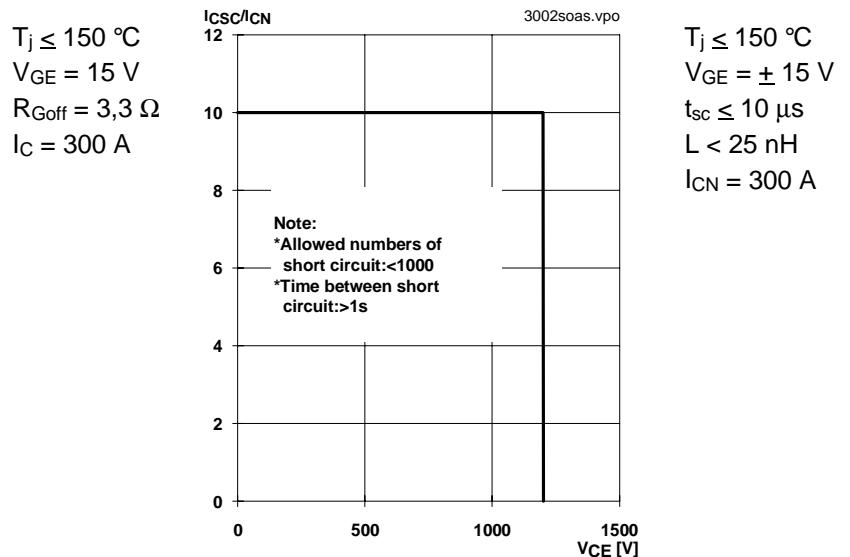


Fig. 6 Safe operating area at short circuit $I_C = f (V_{CE})$

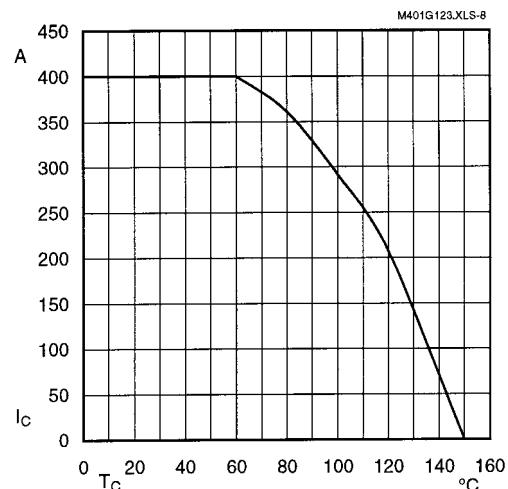


Fig. 8 Rated current vs. temperature I_C = f (T_C)

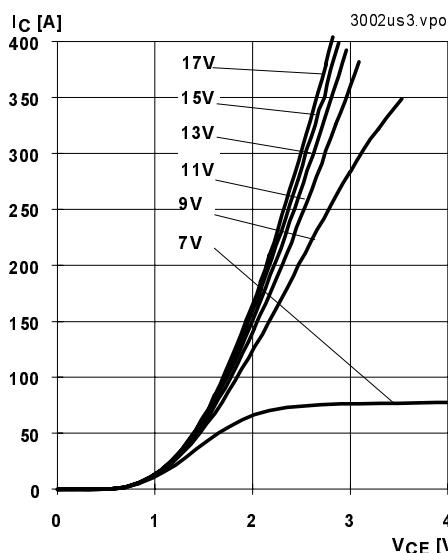


Fig. 9 Typ. output characteristic, t_p = 80 μs; 25 °C

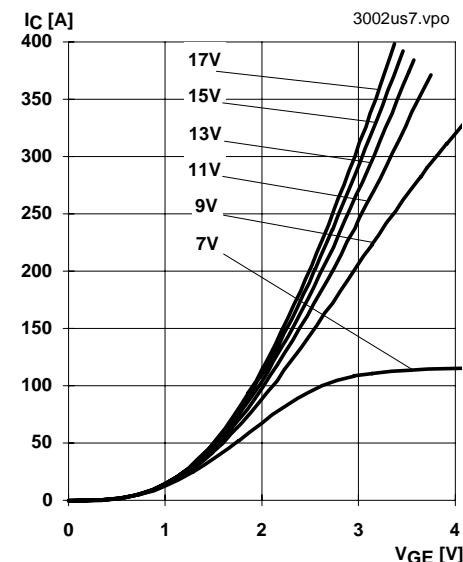


Fig. 10 Typ. output characteristic, t_p = 80 μs; 125 °C

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_{C(t)}$$

$$V_{CEsat(t)} = V_{CE(TO)(T_j)} + r_{CE(T_j)} \cdot I_{C(t)}$$

$$V_{CE(TO)(T_j)} \leq 1,5 + 0,002 (T_j - 25) [V]$$

$$\text{typ.: } r_{CE(T_j)} = 0,0033 + 0,000013 (T_j - 25) [\Omega]$$

$$\text{max.: } r_{CE(T_j)} = 0,0050 + 0,000017 (T_j - 25) [\Omega]$$

valid for V_{GE} = + 15 \pm 2 [V]; I_C > 0,3 I_{Cnom}

Fig. 11 Saturation characteristic (IGBT)
Calculation elements and equations

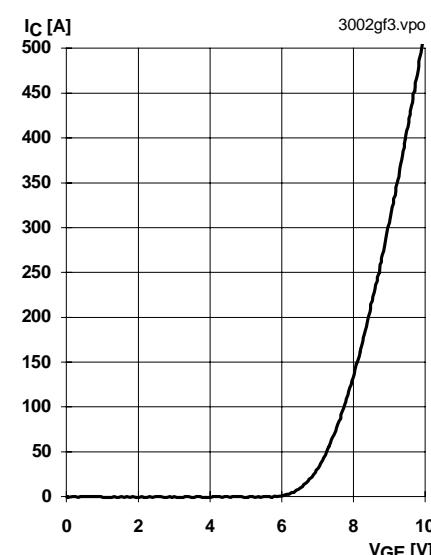


Fig. 12 Typ. transfer characteristic, t_p = 80 μs; V_{CE} = 20 V

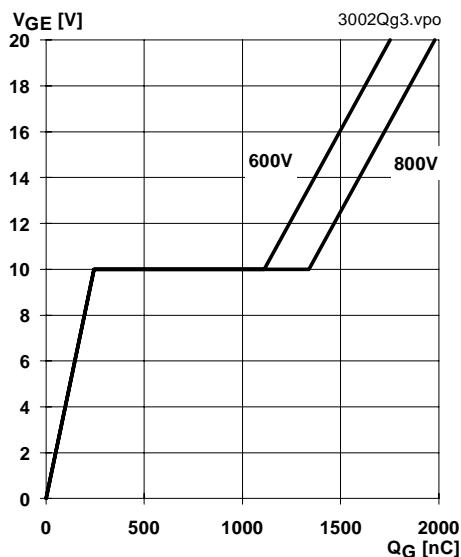


Fig. 13 Typ. gate charge characteristic

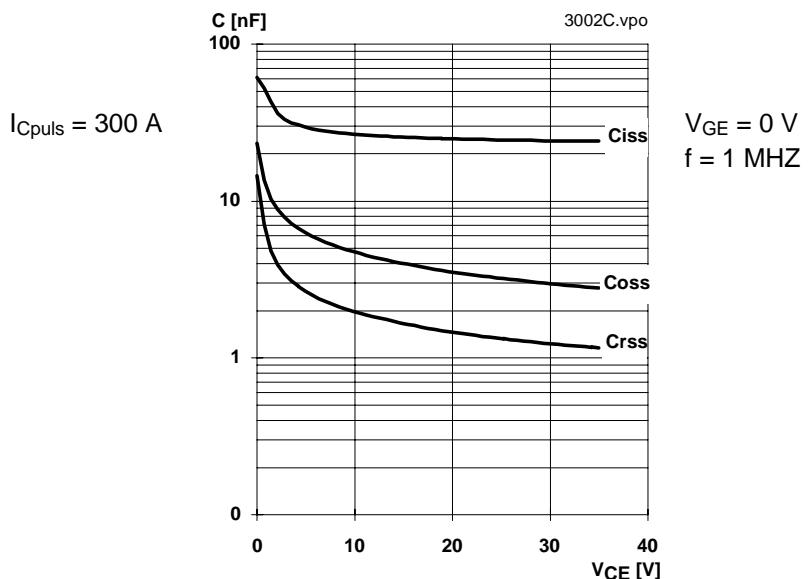


Fig. 14 Typ. capacitances vs. V_{CE}

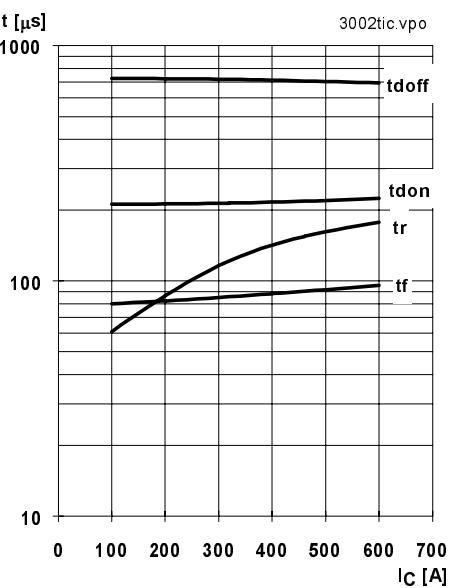


Fig. 15 Typ. switching times vs. I_C

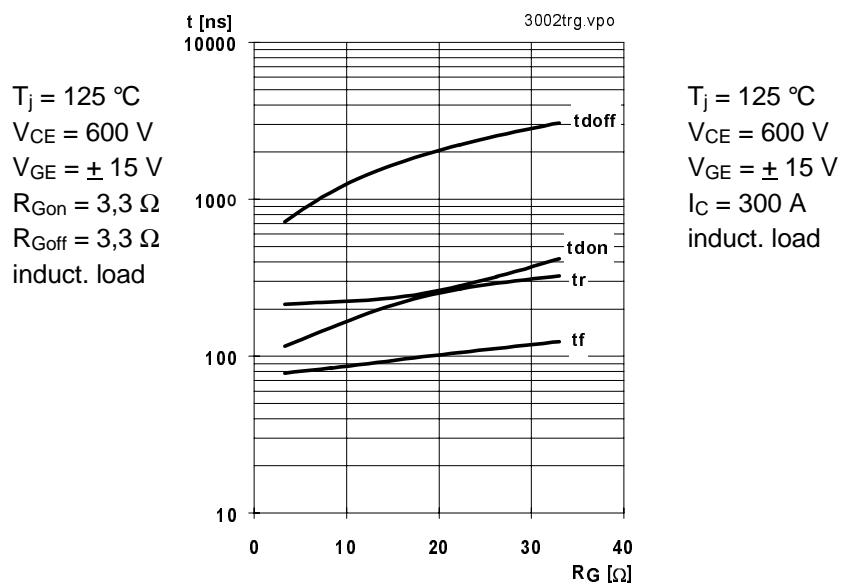


Fig. 16 Typ. switching times vs. gate resistor R_G

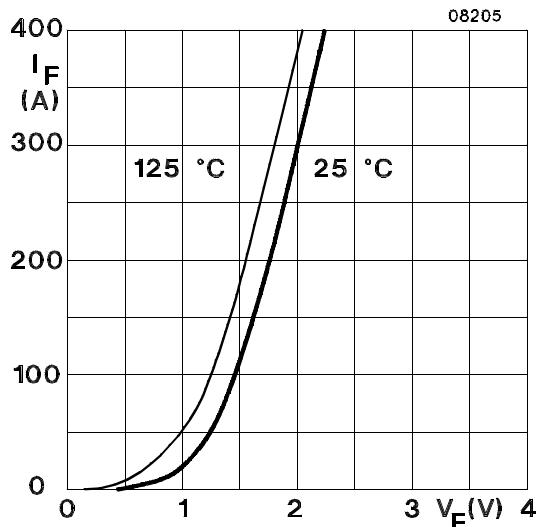


Fig. 17 Typ. CAL diode forward characteristic

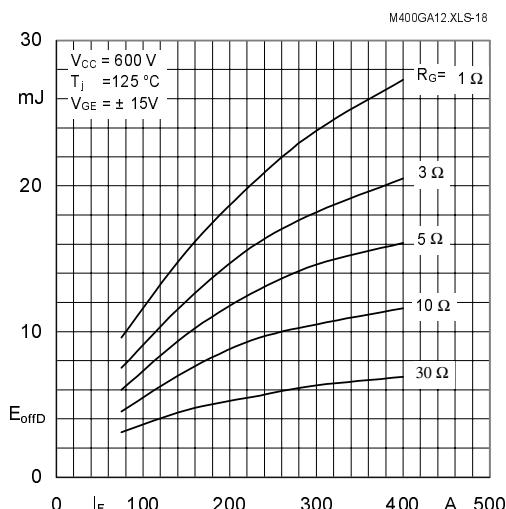


Fig. 18 Diode turn-off energy dissipation per pulse

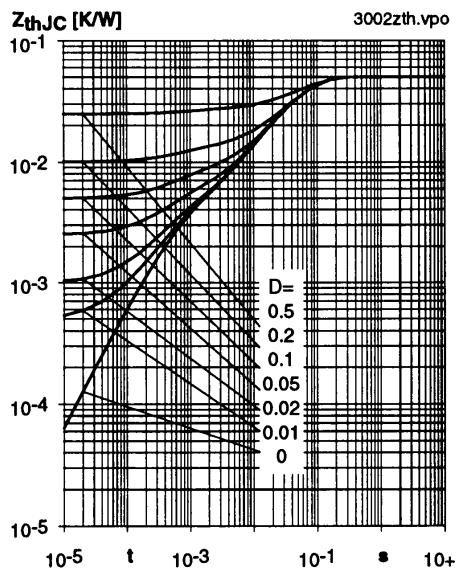


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

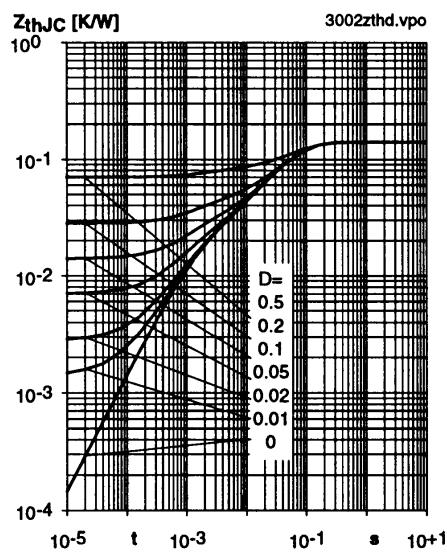


Fig. 20 Transient thermal impedance of
inverse CAL diodes $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

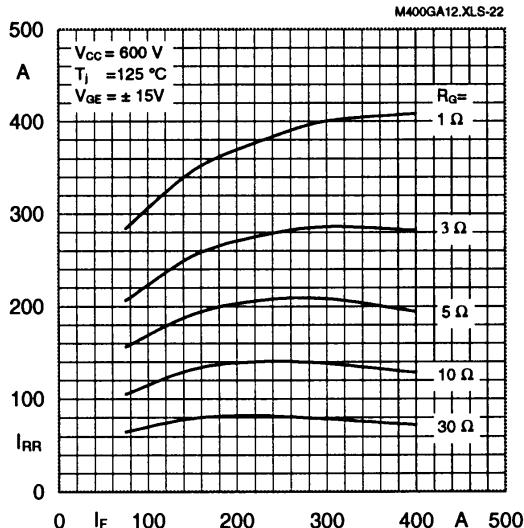


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

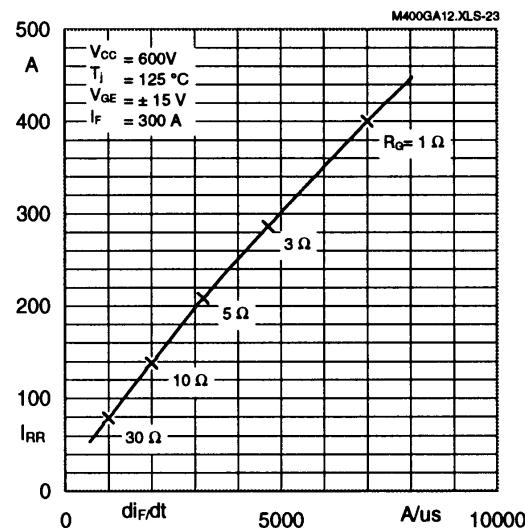


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(dI/dt)$

Typical Applications include

Switched mode power supplies
DC servo and robot drives
Inverters
DC choppers
AC motor speed control
Inductive heating
UPS Uninterruptable power supplies
General power switching applications
Electronic (also portable) welders

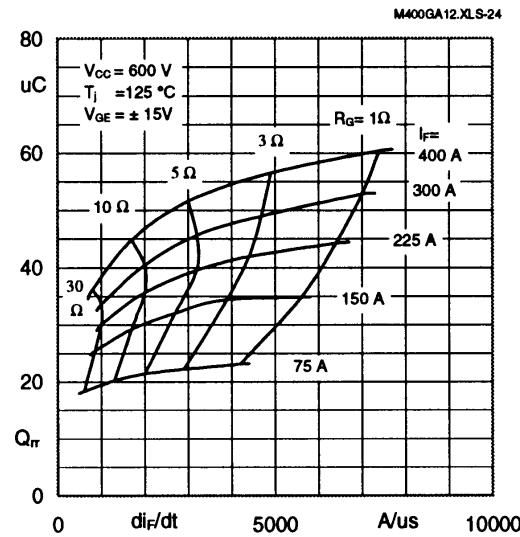


Fig. 24 Typ. CAL diode recovered charge

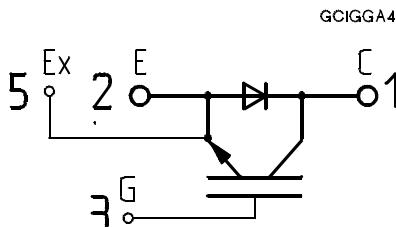
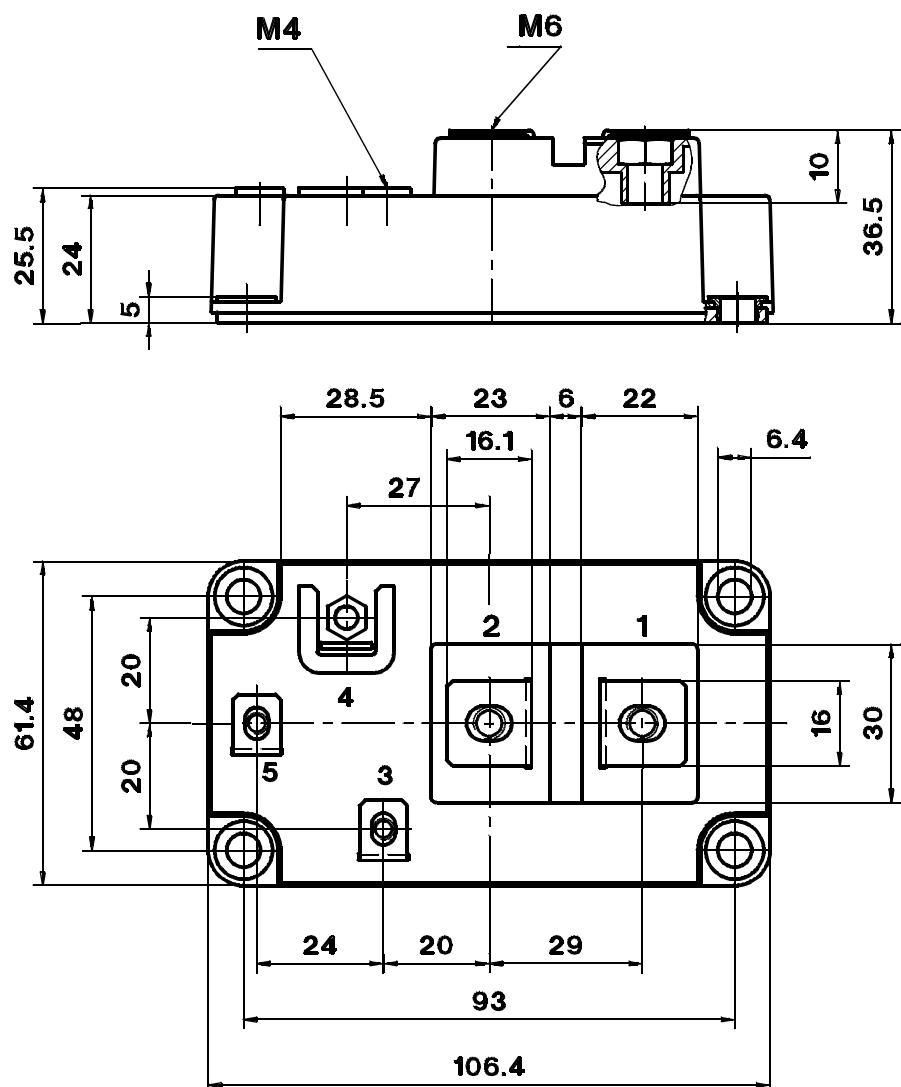
SEMITRANS 4

Case D 59

UL Recognized

File no. E 63 532

CASED59

SKM 200 GA 123 D**SKM 300 GA 123 D****SKM 300 GA 173 D****SKM 400 GA 123 D****SKM 400 GA 173 D**

Dimensions in mm

Option on request:
Terminal 4 = collector sense V_{CE} , add suffix "S". (see B 6 – 212)

Outline and circuit

Mechanical Data			Values	Units	This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.
Symbol	Conditions		min.	typ.	
M ₁	to heatsink, SI Units to heatsink, US Units	(M6)	3 27	— —	5 44 Nm lb.in.
M ₂	for terminals, SI Units for terminals US Units	(M6/M4)	2,5/1,1 22/10	— —	5/2 44/18 Nm lb.in.
a			—	—	5x9,81 m/s^2
w			—	—	330 g

Three devices are supplied in one SEMIBOX B without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 4). Larger packing units of 12 and 20 pieces are used if suitable
Accessories → B 6 - 4.
SEMIBOX B → C - 2.